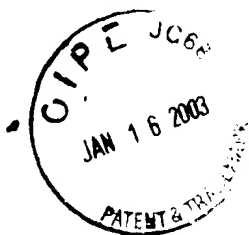


2829



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Tawfik R. Arabi et al.  
Title: AC TESTING OF LEAKAGE CURRENT  
Docket No.: 884.410US1  
Filed: April 19, 2001  
Examiner: Russell Kobert

Serial No.: 09 838,730  
Due Date: January 10, 2003  
Group Art Unit: 2829

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TECHNICAL CENTER 2800

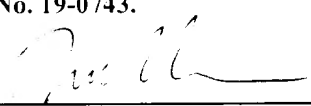
Commissioner for Patents  
Washington, D.C. 20231

We are transmitting herewith the following attached items (as indicated with an "X"):

- ☒ A return postcard.
- ☒ Response to Restriction Requirement (4 Pages).
- ☒ Clean Version of Amended Specification Paragraphs (1 pg.).

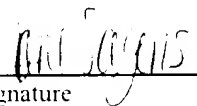
Please consider this a **PETITION FOR EXTENSION OF TIME** for sufficient number of months to enter these papers and please charge any additional required fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.  
P.O. Box 2938, Minneapolis, MN 55402 (612-373-6900)

By:   
Viet V. Tong  
Reg. No. 45,416

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on this 16 day of January, 2003.

Jane Sagers  
Name

  
Signature

**Customer Number 21186**

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.  
(GENERAL)

P.O. Box 2938, Minneapolis, MN 55402 (612-373-6900)



09/838730

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Tawfik R. Arabi et al.

Examiner: Russell Kobert

Serial No.: 09/838730

Group Art Unit: 2829

Filed: April 19, 2001

Docket: 884.410US1

Title: AC TESTING OF LEAKAGE CURRENT

#3  
Election/A  
D.S. mails Logon  
PATENT 1-22-03**RESPONSE TO RESTRICTION REQUIREMENT  
AND PRELIMINARY AMENDMENT**Commissioner for Patents  
Washington, D.C. 20231RECEIVED  
JAN 17 2003  
TECHNOLOGY CENTER 2800

In response to the Restriction Requirement mailed December 10, 2002, Applicant elects without traverse, invention I, species 1 including claims 1-9. Applicant cancels claims 10-20 without prejudice or disclaimer, and reserves the right to reintroduce them in one or more divisional applications at a later date.

Please amend the application as follows:

**IN THE SPECIFICATION**

Please make the paragraph substitutions indicated in the appendix entitled Clean Version of Amended Specification Paragraphs. The specific changes incorporated in the substitute paragraphs are shown in the following marked-up versions of the original paragraphs.

**The paragraph beginning on page 5, line 6 is amended as follows:**

**Pin to Vcc or Pin to Vss test**

In general, at the beginning of the test, a pin is tri-stated or floated. The pin is subsequently driven to a known state with a Boundary Scan pattern (Vss, Vcc, low, or high) for a first predetermined time. After the pin reaches the known state, it is allowed to float or to be unconnected. If the pin has the defect being [test] tested for, it leaks and eventually changes from one state to the other state. At a second predetermined time, the pin is sampled with Boundary Scan. In other words, the voltage value of the pin is measured by internal circuitry of the IC to determine its state at the second predetermined time. Based on the state (measured voltage) of the pin, a pass fail result is determined. In the following detailed description, for simplicity, only leakage testing of pin 122-0 is described; other pins (122 1-N) are tested in the same manner. In one embodiment, only input output pins of IC 120 are tested with Boundary Scan.